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IBM Docket No. FIS920030423US1

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of: **Christopher P. Ausschnitt**

Serial No.: **10/771,684**

Date: **January 24, 2006**

Filed: **February 3, 2004**

Group Art Unit: **2851**  
Batch No.:

Title: **Method of Patterning Process  
Metrology Based on the Intrinsic Focus Offset**

Examiner: **Kevin C. Gutierrez**

**DeLIO & PETERSON, LLC**  
121 Whitney Avenue  
New Haven, CT 06510-1241

**LETTER TO OFFICIAL DRAFTSMAN**

**Mail Stop ISSUE FEE**

Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

Dear Sir:

Applicants are herewith submitting 7 Replacement sheets of Formal Drawings for the approval of the Draftsman.

Please charge the Assignee IBM Corporation Deposit Account No. **09-0458** for any fee related to the acceptance of the attached Formal Drawings. A duplicate copy of this letter is enclosed for that purpose.

Respectfully submitted,

BY:

Attorney: **Peter W. Peterson**  
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